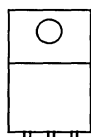


### Product Summary

$V_{DS}$ (V)	$r_{DS(on)}$ ( $\Omega$ )	$I_D$ (A)
100	0.065	30

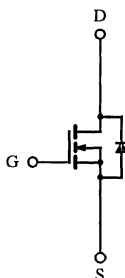
TO-254AA  
Hermetic Package



Case Isolated

D S G

Top View



N-Channel MOSFET

### Absolute Maximum Ratings ( $T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current ( $T_J = 150^\circ\text{C}$ )	$I_D$	$T_C = 25^\circ\text{C}$	30
		$T_C = 100^\circ\text{C}$	24
Pulsed Drain Current	$I_{DM}$	120	A
Maximum Power Dissipation	$P_D$	$T_C = 25^\circ\text{C}$	150
		$T_C = 100^\circ\text{C}$	60
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 to 150	$^\circ\text{C}$
Lead Temperature ( $1/16''$ from case for 10 sec.)	$T_L$	300	

**6**  
N-/P-Channel  
MOSFETs

### Thermal Resistance Ratings

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient	$R_{thJA}$		50	$^\circ\text{C/W}$
Maximum Junction-to-Case	$R_{thJC}$		0.83	
Case-to-Sink	$R_{thCS}$	0.2		

## 2N7075

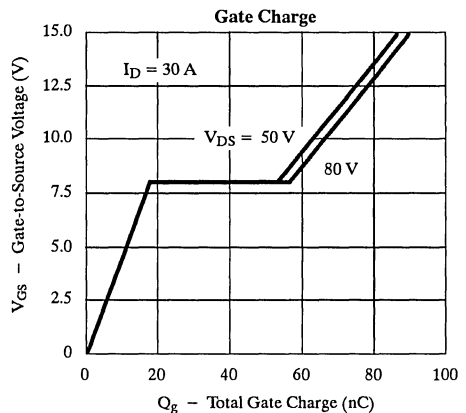
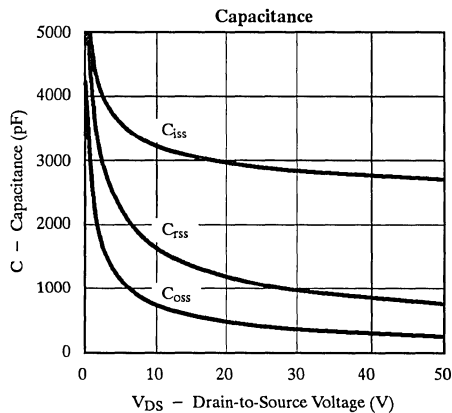
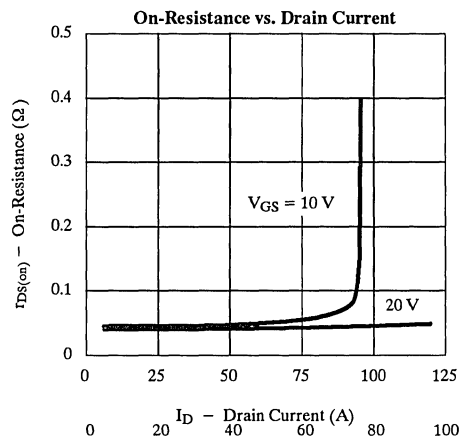
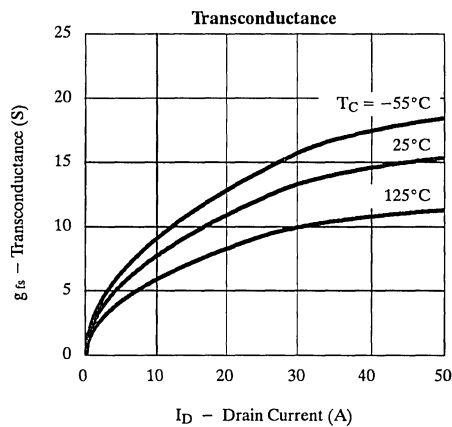
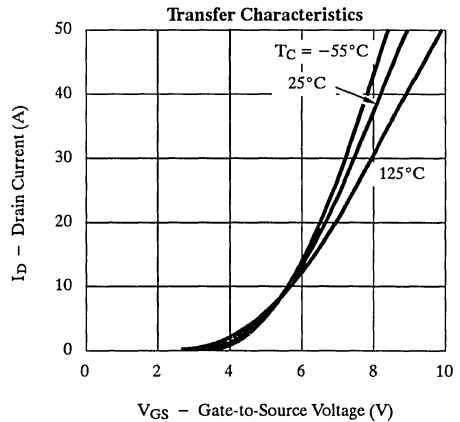
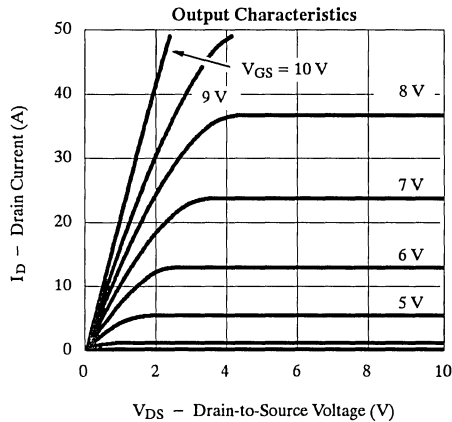
### Specifications ( $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Limit			Unit
			Min	Typ <sup>a</sup>	Max	
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	2.0		4.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 80\text{ V}, V_{GS} = 0\text{ V}$			25	$\mu\text{A}$
		$V_{DS} = 80\text{ V}, V_{GS} = 0\text{ V}, T_J = 125^\circ\text{C}$			250	
On-State Drain Current <sup>b</sup>	$I_{D(on)}$	$V_{DS} = 5\text{ V}, V_{GS} = 10\text{ V}$	30			A
Drain-Source On-State Resistance <sup>b</sup>	$r_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 24\text{ A}$		0.053	0.065	$\Omega$
		$V_{GS} = 10\text{ V}, I_D = 24\text{ A}, T_J = 125^\circ\text{C}$		0.08	0.10	
Forward Transconductance <sup>b</sup>	$g_{fs}$	$V_{DS} = 15\text{ V}, I_D = 24\text{ A}$	9	11	27	S
<b>Dynamic</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1\text{ MHz}$		2800		pF
Output Capacitance	$C_{oss}$			1100		
Reverse Transfer Capacitance	$C_{rss}$			400		
Total Gate Charge <sup>c</sup>	$Q_g$	$V_{DS} = 50\text{ V}, V_{GS} = 10\text{ V}, I_D = 30\text{ A}$		62	125	nC
Gate-Source Charge <sup>c</sup>	$Q_{gs}$			17	22	
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$			35	65	
Turn-On Delay Time <sup>c</sup>	$t_{d(on)}$	$V_{DD} = 50\text{ V}, R_L = 1.67\ \Omega$ $I_D \cong 30\text{ A}, V_{GEN} = 10\text{ V}, R_G = 2.4\ \Omega$		15	35	ns
Rise Time <sup>c</sup>	$t_r$			80	150	
Turn-Off Delay Time <sup>c</sup>	$t_{d(off)}$			60	125	
Fall Time <sup>c</sup>	$t_f$			50	100	
<b>Source-Drain Diode Ratings and Characteristics</b>						
Continuous Current	$I_S$				30	A
Pulsed Current	$I_{SM}$				120	
Diode Forward Voltage <sup>b</sup>	$V_{SD}$	$I_F = 30\text{ A}, V_{GS} = 0\text{ V}$	0.6		1.9	V
Reverse Recovery Time	$t_{rr}$	$I_F = 30\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$		180	400	ns
Reverse Recovery Charge	$Q_{rr}$			0.6		

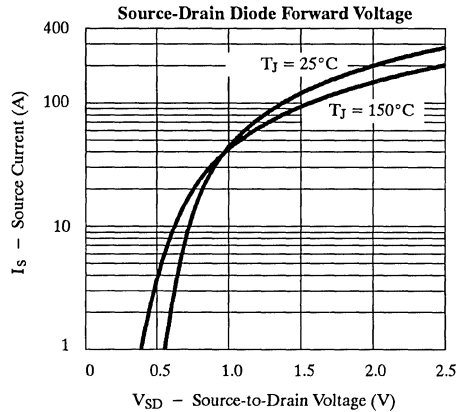
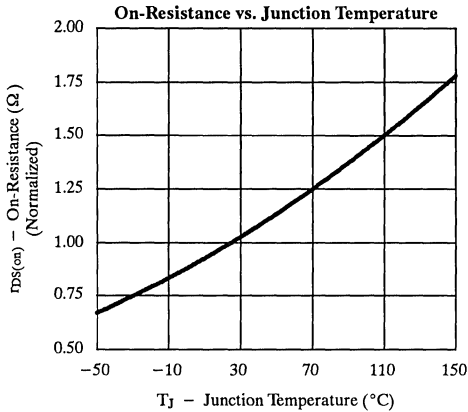
Notes:

- For design aid only; not subject to production testing.
- Pulse test; pulse width  $\leq 300\ \mu\text{s}$ , duty cycle  $\leq 2\%$ .
- Independent of operating temperature.

## Typical Characteristics (25°C Unless Otherwise Noted)



### Typical Characteristics (25°C Unless Otherwise Noted)



### Thermal Ratings

